

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Keizo Yamada

Serial No.: 09/865,528

Filed: May 29, 2001

For: SEMICONDUCTOR DEVICE TEST METHOD AND SEMICONDUCTOR DEVICE
TESTER

Honorable Commissioner of Patents
Washington, D.C. 20231



Group Art Unit: 2829

Examiner: Nguyen, Vinh P.

9/B
G. Stutz
22603

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AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action dated December 26, 2002, please amend the above-identified application as follows:

IN THE CLAIMS:

Please amend claims 1 and 14 as follows:

1. (Amended) A semiconductor device tester comprising:
- electron beam irradiation means for irradiating a test sample with an electron beam;
- current measuring means for measuring current generated in said test sample by said electron beam;
- memory means for storing current waveforms for each of a plurality of test samples, wherein said current waveforms comprise variations of said measured current for each of said plurality of test samples in correspondence with irradiation positions of said electron beam; and

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01 FC:1202
02 FC:1201

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